

## **Product Description**

Peregrine's PE83340 is a high performance integer-N PLL capable of frequency synthesis up to 3.0 GHz. The superior phase noise performance of the PE83340 makes it ideal for applications such as wireless local loop basestations, LMDS systems and other demanding terrestrial systems.

The PE83340 features a 10/11 dual modulus prescaler, counters and a phase comparator as shown in Figure 1. Counter values are programmable through a three wire serial interface.

The PE83340 is optimized for stringent military environments. Fabricated in Peregrine's patented UTSi<sup>®</sup> (Ultra Thin Silicon) CMOS technology, the PE83340 offers excellent RF performance with the economy and integration of conventional CMOS.

# **PRODUCT SPECIFICATON**

# PE83340

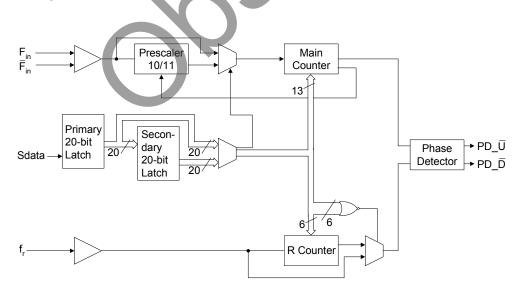
Military Operating Temperature Range

3.0 GHz Integer-N PLL for Low Phase Noise Applications

#### Features

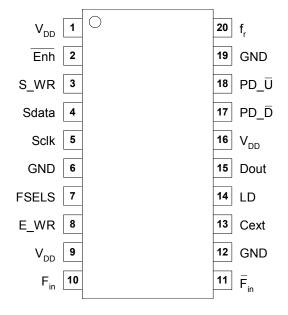
- 3.0 GHz operation
- ÷10/11 dual modulus prescaler
- Internal phase detector
- Serial programmable
- Low power 20 mA at 3 V
- Ultra-low phase noise
- Available in 20-lead TSSOP

#### Figure 1. Block Diagram





#### Figure 2. Pin Configuration



# Table 1. Pin Descriptions

V <sub>DD</sub>	9		12 GND
F <sub>in</sub>	10		
Table 1.	. Pin Descr	iptions	
Pin No.	Pin Name	Туре	Description
1	V <sub>DD</sub>	(Note 1)	Power supply input. Input may range from 2.85 V to 3.15 V. Bypassing required.
2	Enh	Input	Enhancement mode. When asserted low ("0"), enhancement register bits are functional. Internal 70 k $\Omega$ pull-up resistor.
3	S_WR	Input	Serial load enable input. While S_WR is "low", Sdata can be serially clocked. Primary register data are transferred to the secondary register on S_WR rising edge.
4	Sdata	Input	Binary serial data input. Input data entered MSB first.
5	Sclk	Input	Serial clock input. Sdata is clocked serially into the 20-bit primary register (E_WR "low") or the 8-bit enhancement register (E_WR "high") on the rising edge of Sclk.
6	GND		Ground.
7	FSELS	Input	Selects contents of primary register (FSELS=1) or secondary register (FSELS=0) for programming of internal counters. Internal 70 k $\Omega$ pull-down resistor.
8	E_WR	Input	Enhancement register write enable. While E_WR is "high", Sdata can be serially clocked into the enhancement register on the rising edge of Sclk. Internal 70 k $\Omega$ pull-down resistor.
9	V <sub>DD</sub>	(Note 1)	Same as pin 1.
10	F <sub>in</sub>	Input	Prescaler input from the VCO. Max frequency input is 3.0 GHz.
11	Fin	Input	Prescaler complementary input. A bypass capacitor should be placed as close as possible to this pin and be connected in series with a 50 $\Omega$ resistor to the ground plane.
12	GND		Ground.
13	Cext	Output	Logical "NAND" of PD_U and PD_D terminated through an on chip, 2 k $\Omega$ series resistor. Connecting Cext to an external capacitor will low pass filter the input to the inverting amplifier used for driving LD.
14	LD	Output	Lock detect is an open drain logical inversion of CEXT. When the loop is in lock, LD is high impedance, otherwise LD is a logic low ("0").
15	Dout	Output	Data out function, Dout, enabled in enhancement mode.
16	V <sub>DD</sub>	(Note 1)	Same as pin 1.



Pin No.	Pin Name	Туре	Description					
17	PD_D	Output	PD_D pulses down when $f_p$ leads $f_c$ .					
18	PD_U	Output	_U pulses down when $f_c$ leads $f_p$ .					
19	GND		Ground.					
20	f <sub>r</sub>	Input	Reference frequency input.					

**Note 1:** V<sub>DD</sub> pins 1, 9, and 16 are connected by diodes and must be supplied with the same positive voltage level.

#### **Table 2. Absolute Maximum Ratings**

Symbol	Parameter/Conditions	Min	Max	Units
V <sub>DD</sub>	Supply voltage	-0.3	4.0	V
Vi	Voltage on any input	-0.3	V <sub>DD</sub> + 0.3	V
I <sub>I</sub>	DC into any input	-10	+10	mA
Ιo	DC into any output	-10	+10	mA
T <sub>stg</sub>	Storage temperature range	-65	150	°C

#### **Table 3. Operating Ratings**

Symbol	Parameter/Conditions	Min	Max	Units
V <sub>DD</sub>	Supply voltage	2.85	3.15	V
T <sub>A</sub>	Operating ambient temperature range	-55	125	°C

#### Table 4. ESD Ratings

Symbol	Parameter/Conditions	Level	Units
$V_{\text{ESD}}$	ESD voltage human body model (Note 1)	1000	V

Note 1: Periodically sampled, not 100% tested. Tested per MIL-STD-883, M3015 C2

#### **Electrostatic Discharge (ESD) Precautions**

When handling this  $UTSi^{\mbox{\ \ embox{\ embox{\ \ embox{\ \ embox{\ embox{\embox{\ embox{\embox{\embox{\embox{\embox\\ embox{\embox{\ embox{\embox{\embox{\embox{\embox\\ embox{\em$ 

# Latch-Up Avoidance

Unlike conventional CMOS devices, *UTSi* <sup>®</sup> CMOS devices are immune to latch-up.



#### **Table 5. DC Characteristics**

 $V_{\text{DD}}$  = 3.0 V, -55° C <  $T_{\text{A}}$  < 125° C, unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Мах	Units
I <sub>DD</sub>	Operational supply current; Prescaler enabled	V <sub>DD</sub> = 2.85 to 3.15 V		20	35	mA
Digital Inputs	S_WR, Sdata, Sclk	•			-1	
VIH	High level input voltage	V <sub>DD</sub> = 2.85 to 3.15 V	0.7 x V <sub>DD</sub>			V
VIL	Low level input voltage	V <sub>DD</sub> = 2.85 to 3.15 V			$0.3 \times V_{DD}$	V
I <sub>IH</sub>	High level input current	V <sub>IH</sub> = V <sub>DD</sub> = 3.15 V			+1	μA
IIL	Low level input current	V <sub>IL</sub> = 0, V <sub>DD</sub> = 3.15 V	-1			μA
Digital inputs	Enh (contains a 70 kΩ pull-up resistor)	<u>.</u>				
V <sub>IH</sub>	High level input voltage	V <sub>DD</sub> = 2.85 to 3.15 V	$0.7 \text{ x V}_{\text{DD}}$			V
VIL	Low level input voltage	V <sub>DD</sub> = 2.85 to 3.15 V			$0.3 \times V_{DD}$	V
l <sub>iH</sub>	High level input current	V <sub>IH</sub> = V <sub>DD</sub> = 3.15 V			+1	μA
I <sub>IL</sub>	Low level input current	V <sub>IL</sub> = 0, V <sub>DD</sub> = 3.15 V	-100			μA
Digital inputs	FSELS, E_WR (contains a 70 k $\Omega$ pull-d	own resistor)				
VIH	High level input voltage	V <sub>DD</sub> = 2.85 to 3.15 V	0.7 x V <sub>DD</sub>			V
V <sub>IL</sub>	Low level input voltage	V <sub>DD</sub> = 2.85 to 3.15 V			$0.3 \times V_{DD}$	V
Iн	High level input current	V <sub>IH</sub> = V <sub>DD</sub> = 3.15 V			+100	μA
l <sub>IL</sub>	Low level input current	V <sub>IL</sub> = 0, V <sub>DD</sub> = 3.15 V	-1			μA
Reference Div	rider input: f <sub>r</sub>					
I <sub>IHR</sub>	High level input current	$V_{IH} = V_{DD} = 3.15 V$			+100	μA
I <sub>ILR</sub>	Low level input current	V <sub>IL</sub> = 0, V <sub>DD</sub> = 3.15 V	-100			μA
Counter and p	bhase detector outputs: Dout, PD_D, PD	_U				
V <sub>OLD</sub>	Output voltage LOW	$I_{out} = 6 \text{ mA}$			0.4	V
V <sub>OHD</sub>	Output voltage HIGH	l <sub>out</sub> = -3 mA	V <sub>DD</sub> - 0.4			V
Lock detect o	utputs: (Cext, LD)					
V <sub>OLC</sub>	Output voltage LOW, Cext	l <sub>out</sub> = 0.1 uA			0.4	V
V <sub>OHC</sub>	Output voltage HIGH, Cext	I <sub>out</sub> = -0.1 uA	V <sub>DD</sub> - 0.4			V
V <sub>OLLD</sub>	Output voltage LOW, LD	I <sub>out</sub> = 1 mA			0.4	V



#### **Table 6. AC Characteristics**

 $V_{DD}$  = 3.0 V, -55° C < T<sub>A</sub> < 125° C, unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Units
Control Interfa	ice and Latches (see Figures 3, 4)		1			
<b>f</b> <sub>Clk</sub>	Serial data clock frequency	(Note 1)			10	MHz
t <sub>CIkH</sub>	Serial clock HIGH time		30			ns
t <sub>ClkL</sub>	Serial clock LOW time		30			ns
t <sub>DSU</sub>	Sdata set-up time to Sclk rising edge		10			ns
t <sub>DHLD</sub>	Sdata hold time after Sclk rising edge		10			ns
t <sub>PW</sub>	S_WR pulse width		30			ns
t <sub>cwr</sub>	Sclk rising edge to S_WR rising edge		30			ns
t <sub>CE</sub>	Sclk falling edge to E_WR transition		30			ns
t <sub>wrc</sub>	S_WR falling edge to Sclk rising edge		30			ns
t <sub>EC</sub>	E_WR transition to Sclk rising edge		30			ns
Main Divider (I	Including Prescaler)	· ·				
Fin	Operating frequency		500		3000	MHz
$P_{Fin}$	Input level range	External AC coupling	-5		5	dBm
		External AC coupling	0		5	dBm
		(85°C < T <sub>A</sub> ≤ 125°C)				
Main Divider (I	Prescaler Bypassed)		1 1			
F <sub>in</sub>	Operating frequency		50		300	MHz
$P_{Fin}$	Input level range	External AC coupling	0		5	dBm
		85°C < T <sub>A</sub> ≤ 125°C	0		5	dBm
		External AC coupling				
Reference Div	ider		1			
f <sub>r</sub>	Operating frequency	(Note 3)			100	MHz
P <sub>fr</sub>	Reference input power (Note 2)	Single ended input	0			dBm
Phase Detecto	pr					
f <sub>c</sub>	Comparison frequency	(Note 3)			20	MHz
SSB Phase No	bise : Output Referred (F <sub>in</sub> = 1.3 GHz, f <sub>r</sub> =	10 MHz, f <sub>c</sub> = 1.25 MHz, LBW = 70 kHz)				
PN <sub>OR</sub>	Output Referred Phase Noise	100 Hz Offset: V <sub>DD</sub> = 3.0V, T = 25°C		-87	(Note 4)	dBc/Hz
PN <sub>OR</sub>	Output Referred Phase Noise	1000 Hz Offset: V <sub>DD</sub> = 3.0V, T = 25°C		-93	(Note 4)	dBc/Hz

Note 1: fclk is verified during the functional pattern test. Serial programming sections of the functional pattern are clocked at 10 MHz to verify fclk specification.

**Note 2:** CMOS logic levels can be used to drive reference input if DC coupled. Voltage input needs to be a minimum of 0.5 Vp-p. For optimum phase noise performance, the reference input falling edge rate should be faster than 80mV/ns.

Note 3: Parameter is guaranteed through characterization only and is not tested.

**Note 4:** All devices are screened to phase noise limits listed in Table 7. The magnitude of the tester uncertainty precludes testing phase noise as part of qualification testing. These parameters are also exempt from PDA requirements.

Table 7. Phase Noise	Test
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Test name	Conditions	Max	Units
Phase Noise	100 Hz Offset	-73	dBc/Hz
	1000 Hz Offset	-83	dBc/Hz

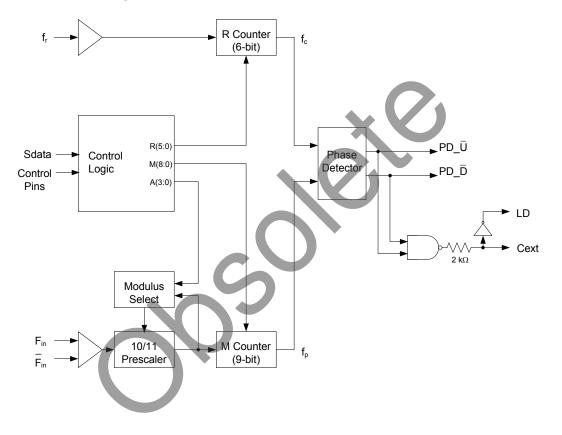


#### **Functional Description**

The *PE83340* consists of a prescaler, counters, a phase detector and control logic. The dual modulus prescaler divides the VCO frequency by either 10 or 11, depending on the value of the modulus select. Counters "R" and "M" divide the reference and prescaler output, respectively, by integer values stored in a 20-bit register. An additional counter ("A") is used in the modulus select logic.

The phase-frequency detector generates up and down frequency control signals. Data is written into the internal registers via the three wire serial bus. There are also various operational and test modes and a lock detect output.

#### Figure 3. Functional Block Diagram



#### **Main Counter Chain**

#### Normal Operating Mode

Setting the Pre\_en control bit "low" enables the  $\div 10/11$  prescaler. The main counter chain then divides the RF input frequency (F<sub>in</sub>) by an integer derived from the values in the "M" and "A" counters.

In this mode, the output from the main counter chain  $(f_p)$  is related to the VCO frequency  $(F_{in})$  by the following equation:

 $f_p = F_{in} / [10 \times (M + 1) + A]$ (1) where  $A \le M + 1, 1 \le M \le 511$ 

When the loop is locked,  $F_{in}$  is related to the reference frequency ( $f_r$ ) by the following equation:

 $F_{in} = [10 \ x \ (M+1) + A] \ x \ (f_r / (R+1))$ (2) where  $A \le M+1, \ 1 \le M \le 511$ 

A consequence of the upper limit on A is that  $F_{in}$  must be greater than or equal to 90 x ( $f_r$  / (R+1)) to obtain contiguous channels. The A counter can accept values as high as 15, but in typical operation it will cycle from 0 to 9 between increments in M.

Programming the M counter with the minimum allowed value of "1" will result in a minimum M counter divide ratio of "2".

#### Prescaler Bypass Mode

Setting the frequency control register bit Pre\_en "high" allows  $F_{in}$  to bypass the  $\pm 10/11$  prescaler. In this mode, the prescaler and A counter are powered down, and the input VCO frequency is divided by the M counter directly. The following equation relates  $F_{in}$  to the reference frequency  $f_r$ :

 $F_{in} = (M + 1) x (f_r / (R+1))$ where  $1 \le M \le 511$  (3)

### **Reference Counter**

The reference counter chain divides the reference frequency  $f_r$  down to the phase detector comparison frequency  $f_c$ .

The output frequency of the 6-bit R Counter is related to the reference frequency by the following equation:

 $f_c = f_r / (R + 1)$ where  $0 \le R \le 63$  (4)

Note that programming R with "0" will pass the reference frequency  $(f_r)$  directly to the phase detector.

#### **Register Programming**

#### Serial Interface Mode

While the E\_WR input is "low" and the S\_WR input is "low", serial input data (Sdata input),  $B_0$  to  $B_{19}$ , are clocked serially into the primary register on the rising edge of Sclk, MSB ( $B_0$ ) first. The contents from the primary register are transferred into the secondary register on the rising edge of either S\_WR according to the timing diagrams shown in Figure 4. Data are transferred to the counters as shown in Table 7 on page 9.

The double buffering provided by the primary and secondary registers allows for "ping-pong" counter control using the FSELS input. When FSELS is "high", the primary register contents set the counter inputs. When FSELS is "low", the secondary register contents are utilized.

While the E\_WR input is "high" and the S\_WR input is "low", serial input data (Sdata input),  $B_0$  to  $B_7$ , are clocked serially into the enhancement register on the rising edge of Sclk, MSB ( $B_0$ ) first. The enhancement register is double buffered to prevent inadvertent control changes during serial loading, with buffer capture of the serially entered data performed on the falling edge of E\_WR according to the timing diagram shown in Figure 4. After the falling edge of E\_WR, the data provide control bits as shown in Table 8 on page 9 will have their bit functionality enabled by asserting the Enh input "low".





## Table 7. Primary Register Programming

Interface Mode	Enh	R₅	R₄	M <sub>8</sub>	M <sub>7</sub>	Pre_en	M <sub>6</sub>	M₅	M4	M <sub>3</sub>	M <sub>2</sub>	M₁	Mo	R <sub>3</sub>	R <sub>2</sub>	R₁	R₀	A <sub>3</sub>	A <sub>2</sub>	<b>A</b> 1	A <sub>0</sub>
Serial*	1	B <sub>0</sub>	B <sub>1</sub>	B <sub>2</sub>	B <sub>3</sub>	B <sub>4</sub>	B <sub>5</sub>	B <sub>6</sub>	B <sub>7</sub>	B <sub>8</sub>	B <sub>9</sub>	B <sub>10</sub>	B <sub>11</sub>	B <sub>12</sub>	B <sub>13</sub>	B <sub>14</sub>	B <sub>15</sub>	B <sub>16</sub>	B <sub>17</sub>	B <sub>18</sub>	B <sub>19</sub>

\*Serial data clocked serially on Sclk rising edge while E\_WR "low" and captured in secondary register on S\_WR rising edge.



(last in) LSB

#### **Table 8. Enhancement Register Programming**

Interface Mode	Enh	Reserved	Reserved	f <sub>p</sub> output	Power down	Counter load	MSEL output	f <sub>c</sub> output	Reserved
Serial*	0	B <sub>0</sub>	B <sub>1</sub>	B <sub>2</sub>	B <sub>3</sub>	B <sub>4</sub>	B <sub>5</sub>	B <sub>6</sub>	B <sub>7</sub>
Serial data clo		ally on Sclk risir	ng edge while E	_WR "high" and	l captured in the	e double buffer o	on E_WR falling	edge.	↓ (last in) LSB
						X	0		、 <i>,</i>
igure 4. S	Serial Ir	nterface Mo	ode Timing	j Diagram					
Sdata		$\times$			$\overline{\cap}$				
E_WR				S	5				
			tec		Γ			t <sub>CE</sub> →	
Sclk									∟
S_WR		t <sub>DSI</sub>	t	DHLD	t <sub>c</sub>	ikh t <sub>CikL</sub>		cwr t <sub>pw</sub>	t <sub>wrc</sub>



#### **Enhancement Register**

The functions of the enhancement register bits are shown below with all bits active "high".

Bit Function		Description		
Bit 0	Reserved**			
Bit 1	Reserved**			
Bit 2	f <sub>p</sub> output	Drives the M counter output onto the Dout output.		
Bit 3	Power down	Power down of all functions except programming interface.		
Bit 4	Counter load	Immediate and continuous load of counter programming.		
Bit 5	MSEL output	Drives the internal dual modulus prescaler modulus select (MSEL) onto the Dout output.		
Bit 6	f <sub>c</sub> output	Drives the reference counter output onto the Dout output		
Bit 7	Reserved**			

\*\* Program to 0

#### Phase Detector

The phase detector is triggered by rising edges from the main Counter  $(f_p)$  and the reference counter  $(f_c)$ . It has two outputs, namely PD\_U, and PD\_D. If the divided VCO leads the divided reference in phase or frequency  $(f_p \text{ leads } f_c)$ , PD\_D pulses "low". If the divided reference leads the divided VCO in phase or frequency  $(f_c \text{ leads } f_p)$ , PD\_U pulses "low". The width of either pulse is directly proportional to phase offset between the two input signals,  $f_p$  and  $f_c$ .

The phase detector gain is equal to 2.70 V /  $2\pi$ , which numerically yields 0.43 V / Radian.

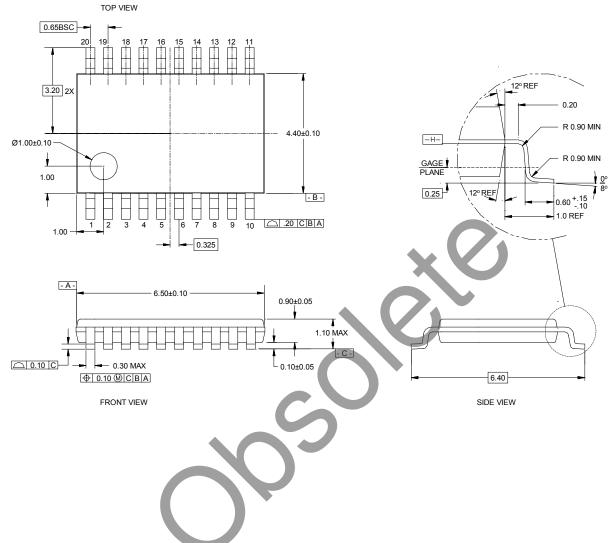
PD\_U and PD\_D drive an active loop filter which controls the VCO tune voltage. PD\_U pulses result in an increase in VCO frequency and PD\_D results in a decrease in VCO frequency, for a positive Kv VCO.

A lock detect output, LD is also provided, via the pin Cext. Cext is the logical "NAND" of PD\_U and PD\_D waveforms, which is driven through a series 2 kohm resistor. Connecting Cext to an external shunt capacitor provides low pass filtering of this signal. Cext also drives the input of an internal inverting comparator with an open drain output. Thus LD is an "AND" function of PD\_U and PD\_D.



### Figure 5. Package Drawing

20-lead TSSOP (JEDEC MO-153-AC)



#### Table 10. Ordering Information

Order Code	Part Marking	Description	Package	Shipping Method
83340-11	PE83340	PE83340-20TSSOP-74A	20-lead TSSOP	74 units / Tube
83340-12	PE83340	PE83340-20TSSOP-200C	20-lead TSSOP	2000 units / T&R
83340-00	PE83340EK	PE83340-20TSSOP-EVAL KIT	20-lead TSSOP	1 / Box

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# **Data Sheet Identification**

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The product is in a formative or design stage. The data sheet contains design target specifications for product development. Specifications and features may change in any manner without notice.

#### **Preliminary Specification**

The data sheet contains preliminary data. Additional data may be added at a later date. Peregrine reserves the right to change specifications at any time without notice in order to supply the best possible product.

#### **Product Specification**

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